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Ghazizadeh

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(54) **MEASUREMENT USING A CALIBRATION PATTERN**

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(51) **Int. Cl.**

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G06K 19/06	(2006.01)
G06T 7/00	(2006.01)
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(52) **U.S. Cl.**

CPC ***G01D 18/00*** (2013.01); ***G01B 21/042*** (2013.01); ***G06K 19/06046*** (2013.01); ***G06T 7/0051*** (2013.01); *G06T 2207/20208* (2013.01)

(58) **Field of Classification Search**

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USPC 235/375, 462.1
See application file for complete search history.

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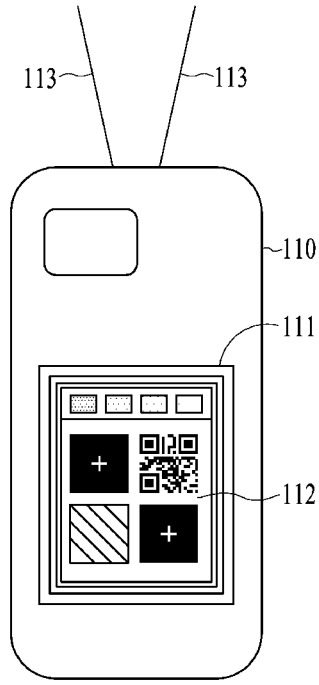
(57) **ABSTRACT**

An image is captured. The image includes a calibration pattern. The calibration pattern includes displayed information about the calibration pattern. The displayed information and the calibration pattern are used to make a calibrated measurement.

8 Claims, 12 Drawing Sheets